

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/682,850	MAAYAH ET AL.	
Examiner	Art Unit	

Sheela C. Chawan

Art Unit 2623

SEADCHED					
SEARCHED					
Class	Subclass	Date	Examiner		
382	145,149	12/28/2005	scc		
382	168	12/28/2005	scc		
356	237.4	12/28/2005	scc		
250	559.22	12/28/2005	scc		
ABOVE	SEARCH	12/28/2005	scc		
UP-DATE,					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
382	145,149	12/28/2005	scc	
382	168	12/28/2005	scc	
356	237.4	12/28/2005	scc	
250/559.22		12/28/2005	scc	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST, US- PGPUB,USPAT,EPO,JPO,DERWENT ,IBM-TDB, SEE SEARCH HISTORY PRINTOUT AND UPDATE THE SEARCH.	12/28/2005	scc
382/141,145,149,168,274,254,232,15 1.CCLS.356/388,394,429,237,237.2, 237.5,237.5,237.4.CCLS.257/184,E21 .525,E21.53.CCLS.	12/28/2005	scc
INVENTOR NAME SEARCH.	12/28/2005	SCC
INSPEC SEARCH.	12/28/2005	scc
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	12/28/2005	scc